


<b>Search Notes</b>  	<b>Application/Control No.</b>  09301656	<b>Applicant(s)/Patent Under Reexamination</b>  WASHINO ET AL.
	<b>Examiner</b>  Nhon T Diep	<b>Art Unit</b>  2621

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with Vo and Rao, 2621 on 101 (method)	1/31/2009	ND

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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